

Notice of References Cited		Application/Control No. 09/665,582	Applicant(s)/Patent Under Reexamination HORTON, JOHN J.	
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*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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B	US-6574197 B1	06-2003	Kanamaru et al.	370/252
C	US-5835721	11-1998	Donahue et al.	709/224
D	US-5959974	09-1999	Badt et al.	370/233
E	US-6205579 B1	03-2001	Southgate	717/11
F	US-6622179 B2	09-2003	Welder	710/15
G	US-6747957 B1	06-2004	Pithawala et al.	709/224
H	US-6654914 B1	11-2003	Kaffine et al.	714/43
I	US-6640239 B1	10-2003	Gidwani	709/203
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	C	US-6606659B1	08-2003	Hegli et al.	709/225
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